

Dual N-Channel Fast Switching MOSFET
General Description

The QM3816N6 is the highest performance trench Dual N-channel MOSFET with extreme high cell density , which provide excellent RDSON and gate charge for most of the synchronous buck converter applications .

The QM3816N6 meet the RoHS and Green Product requirement with full function reliability approved.

Features

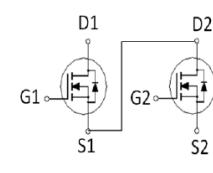
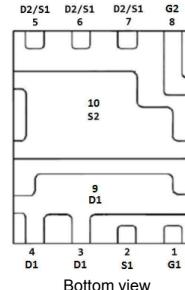
- Advanced high cell density Trench technology
- Super Low Gate Charge
- Excellent CdV/dt effect decline
- Green Device Available

Product Summary


	BVDSS	RDSON (VGS=10V)	ID (Tc=25°C)
Die1	30V	7.3mΩ	51A
Die2	30V	1.9mΩ	117A

Applications

- High Frequency Point-of-Load Synchronous Buck Converter for MB/NB/UMPC/VGA
- Networking DC-DC Power System
- CCFL Back-light Inverter

DFN 5X6 Pin Configuration

Absolute Maximum Ratings(T_J=25 °C, unless otherwise noted)

Symbol	Parameter	Rating		Units
		Die1	Die2	
V _{DS}	Drain-Source Voltage	30	30	V
V _{GS}	Gate-Source Voltage	±20	±20	V
I _D @T _C =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	51	117	A
I _D @T _C =100°C	Continuous Drain Current, V _{GS} @ 10V ¹	32	74	A
I _D @T _A =25°C	Continuous Drain Current, V _{GS} @ 10V ¹	13	28	A
I _D @T _A =70°C	Continuous Drain Current, V _{GS} @ 10V ¹	10	22	A
I _{DM}	Pulsed Drain Current ²	102	234	A
EAS	Single Pulse Avalanche Energy ³	59.5	519.2	mJ
I _{AS}	Avalanche Current	34.5	101.9	A
P _D @T _C =25°C	Total Power Dissipation ⁴	31	40	W
P _D @T _A =25°C	Total Power Dissipation ⁴	2	2	W
T _{STG}	Storage Temperature Range	-55 to 150	-55 to 150	°C
T _J	Operating Junction Temperature Range	-55 to 150	-55 to 150	°C

Thermal Data

Symbol	Parameter	Die 1	Die 2	Unit
R _{θJA}	Thermal Resistance Junction-Ambient ¹	62	56	°C/W
R _{θJC}	Thermal Resistance Junction-Case ¹	4	3.1	°C/W

Dual N-Channel Fast Switching MOSFET
Die1 N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BV_{DSS} Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	---	0.03	---	$\text{V}/^\circ\text{C}$
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{GS}=10\text{V}$, $I_D=30\text{A}$	---	5.8	7.3	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=15\text{A}$	---	9.0	11.7	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	1.2	---	2.5	V
$\Delta V_{GS(\text{th})}/\Delta T_J$	$V_{GS(\text{th})}$ Temperature Coefficient		---	-5.5	---	$\text{mV}/^\circ\text{C}$
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$	---	---	1	uA
		$V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=30\text{A}$	---	31	---	S
R_g	Gate Resistance	$V_{DS}=0\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	1.2	---	Ω
Q_g	Total Gate Charge (10V)	$V_{DS}=15\text{V}$, $V_{GS}=10\text{V}$, $I_D=15\text{A}$	---	18.3	---	nC
Q_g	Total Gate Charge (4.5V)	$V_{DS}=15\text{V}$, $V_{GS}=4.5\text{V}$, $I_D=15\text{A}$	---	9.1	---	nC
Q_{gs}	Gate-Source Charge		---	3.7	---	
Q_{gd}	Gate-Drain Charge		---	3.6	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=15\text{V}$, $V_{GS}=10\text{V}$, $R_G=3.3\Omega$ $I_D=15\text{A}$	---	7.7	---	ns
T_r	Rise Time		---	37.7	---	
$T_{d(off)}$	Turn-Off Delay Time		---	22.4	---	
T_f	Fall Time		---	9.8	---	
C_{iss}	Input Capacitance	$V_{DS}=15\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	1022	---	pF
C_{oss}	Output Capacitance		---	160	---	
C_{rss}	Reverse Transfer Capacitance		---	106	---	

Guaranteed Avalanche Characteristics($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	$V_{DD}=25\text{V}$, $L=0.1\text{mH}$, $I_{AS}=24\text{A}$	28.8	---	---	mJ

Diode Characteristics($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,6}	$V_G=V_D=0\text{V}$, Force Current	---	---	51	A
			---	---	102	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0\text{V}$, $I_s=1\text{A}$	---	---	1.2	V

Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=25\text{V}, V_{GS}=10\text{V}, L=0.1\text{mH}$.
- 4.The power dissipation is limited by 150°C junction temperature
- 5.The Min. value is 100% EAS tested guarantee.
- 6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

Dual N-Channel Fast Switching MOSFET
Die2 N-Channel Electrical Characteristics ($T_J=25^\circ\text{C}$, unless otherwise noted)

Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
BV_{DSS}	Drain-Source Breakdown Voltage	$V_{GS}=0\text{V}$, $I_D=250\mu\text{A}$	30	---	---	V
$\Delta BV_{DSS}/\Delta T_J$	BVDSS Temperature Coefficient	Reference to 25°C , $I_D=1\text{mA}$	---	0.03	---	V°C
$R_{DS(\text{ON})}$	Static Drain-Source On-Resistance ²	$V_{GS}=10\text{V}$, $I_D=30\text{A}$	---	1.5	1.9	$\text{m}\Omega$
		$V_{GS}=4.5\text{V}$, $I_D=15\text{A}$	---	2.2	2.9	
$V_{GS(\text{th})}$	Gate Threshold Voltage	$V_{GS}=V_{DS}$, $I_D=250\mu\text{A}$	1.2	---	2.5	V
$\Delta V_{GS(\text{th})}$	$V_{GS(\text{th})}$ Temperature Coefficient		---	6.0	---	mV°C
I_{DSS}	Drain-Source Leakage Current	$V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$	---	---	1	uA
		$V_{DS}=24\text{V}$, $V_{GS}=0\text{V}$, $T_J=55^\circ\text{C}$	---	---	5	
I_{GSS}	Gate-Source Leakage Current	$V_{GS}=\pm 20\text{V}$, $V_{DS}=0\text{V}$	---	---	± 100	nA
g_{fs}	Forward Transconductance	$V_{DS}=5\text{V}$, $I_D=30\text{A}$	---	115	---	S
R_g	Gate Resistance	$V_{DS}=0\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	0.7	---	Ω
Q_g	Total Gate Charge (10V)	$V_{DS}=15\text{V}$, $V_{GS}=10\text{V}$, $I_D=15\text{A}$	---	80.7	---	nC
Q_g	Total Gate Charge (4.5V)	$V_{DS}=15\text{V}$, $V_{GS}=4.5\text{V}$, $I_D=15\text{A}$	---	40.7	---	nC
Q_{gs}	Gate-Source Charge		---	14.7	---	
Q_{gd}	Gate-Drain Charge		---	16.2	---	
$T_{d(on)}$	Turn-On Delay Time	$V_{DD}=15\text{V}$, $V_{GS}=10\text{V}$, $R_G=3.3\Omega$	---	19.1	---	ns
T_r	Rise Time		---	51.6	---	
$T_{d(off)}$	Turn-Off Delay Time		---	68.6	---	
T_f	Fall Time		---	22.5	---	
C_{iss}	Input Capacitance	$V_{DS}=15\text{V}$, $V_{GS}=0\text{V}$, $f=1\text{MHz}$	---	4982	---	pF
C_{oss}	Output Capacitance		---	763	---	
C_{rss}	Reverse Transfer Capacitance		---	468	---	

Guaranteed Avalanche Characteristics($T_J=25^\circ\text{C}$, unless otherwise noted)

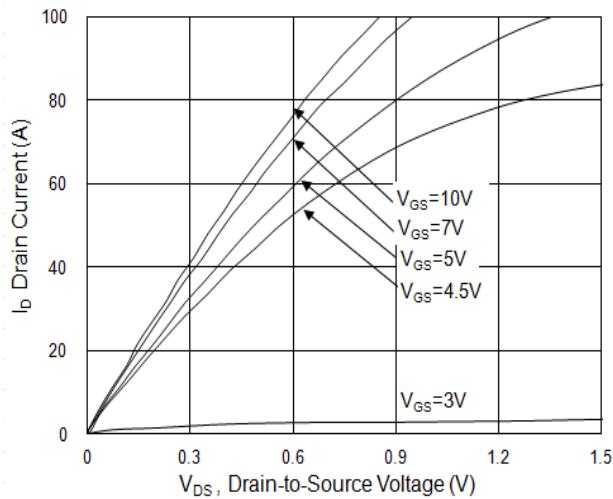
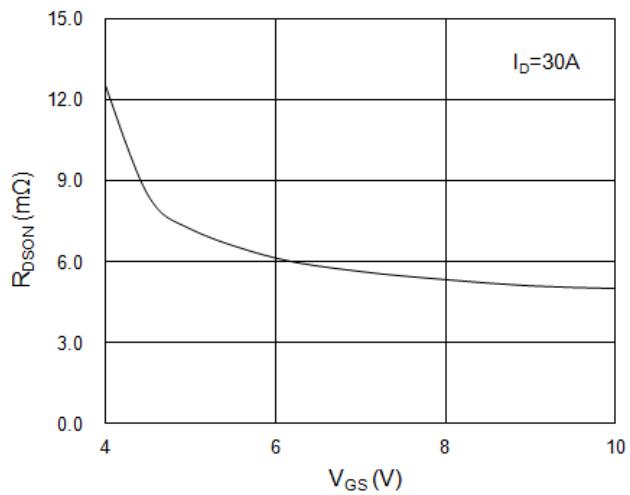
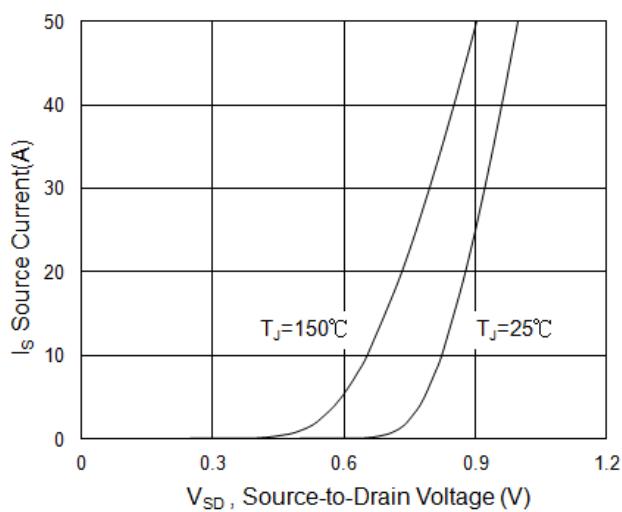
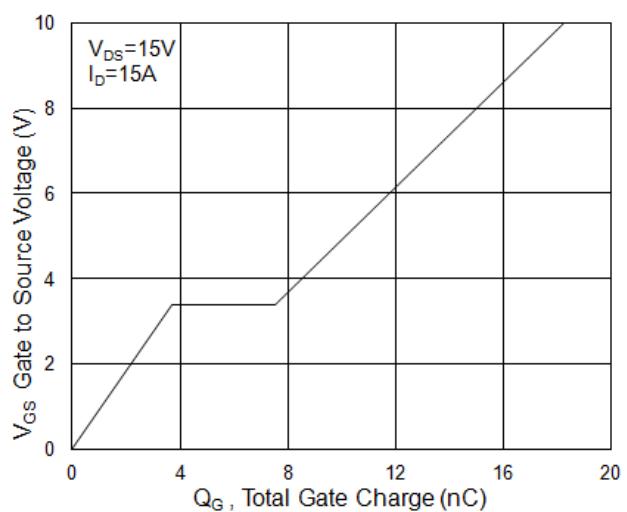
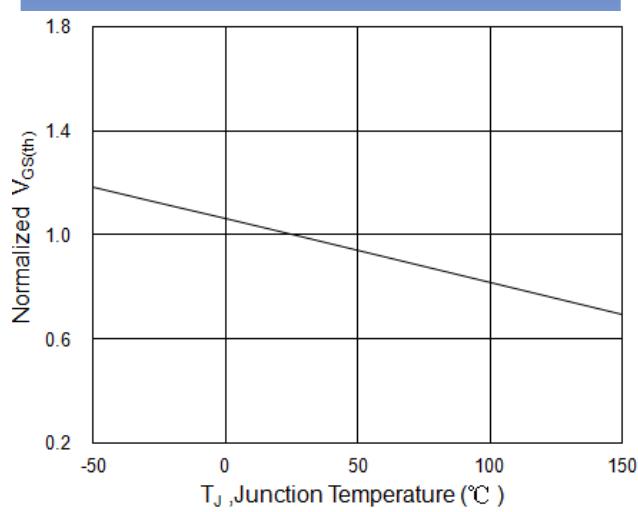
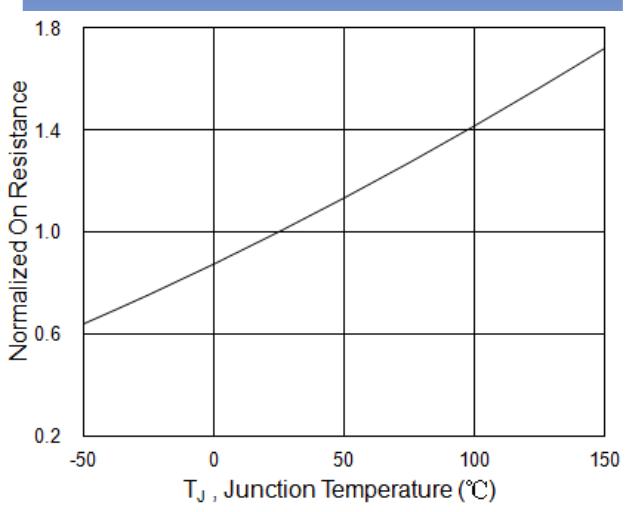
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
EAS	Single Pulse Avalanche Energy ⁵	$V_{DD}=25\text{V}$, $L=0.1\text{mH}$, $I_{AS}=72\text{A}$	259.2	---	---	mJ

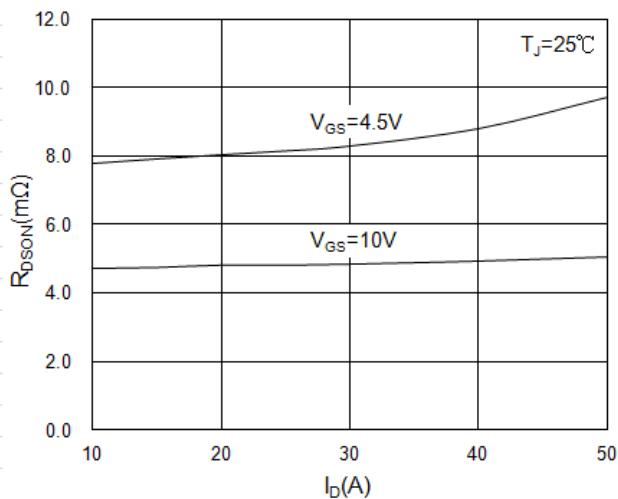
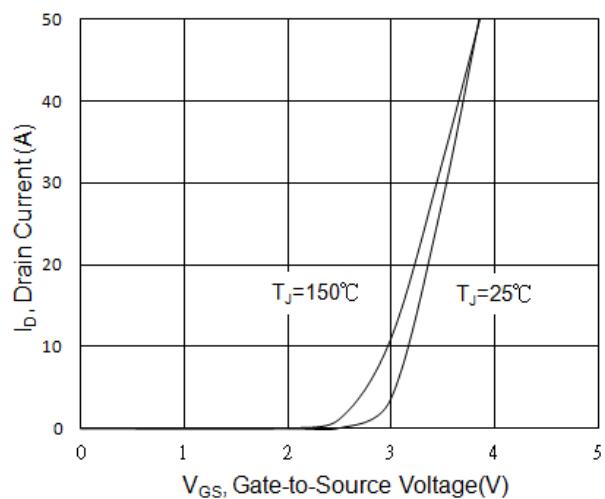
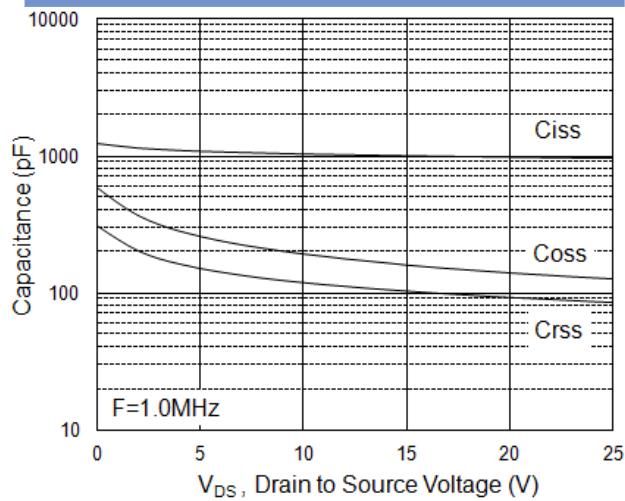
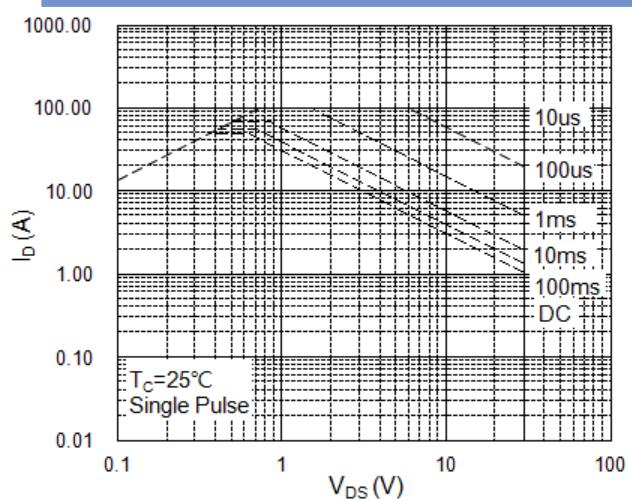
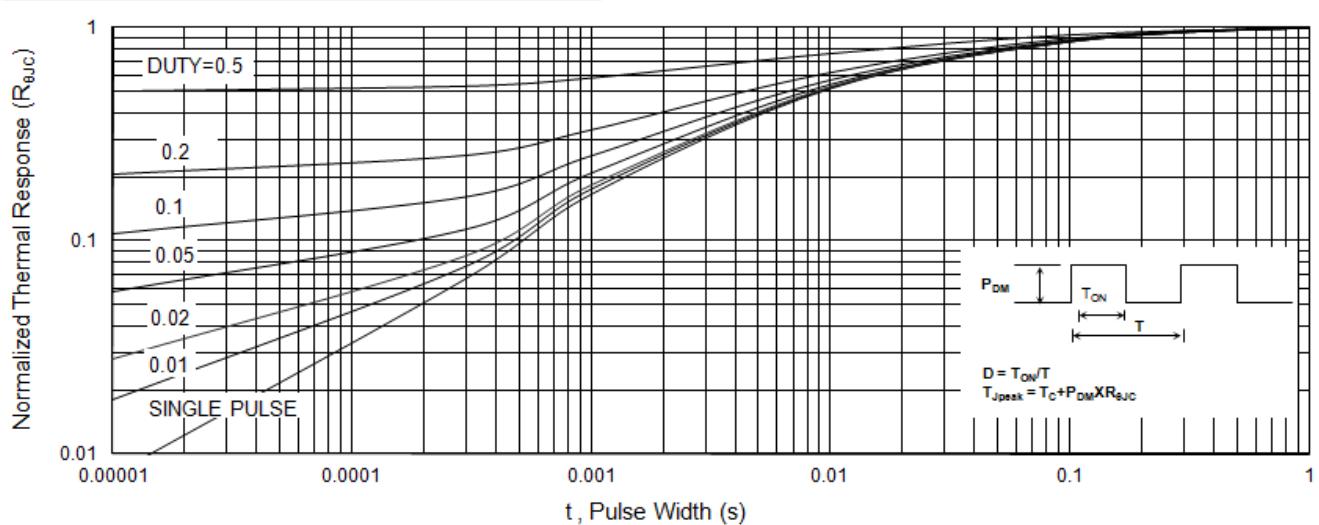
Diode Characteristics($T_J=25^\circ\text{C}$, unless otherwise noted)

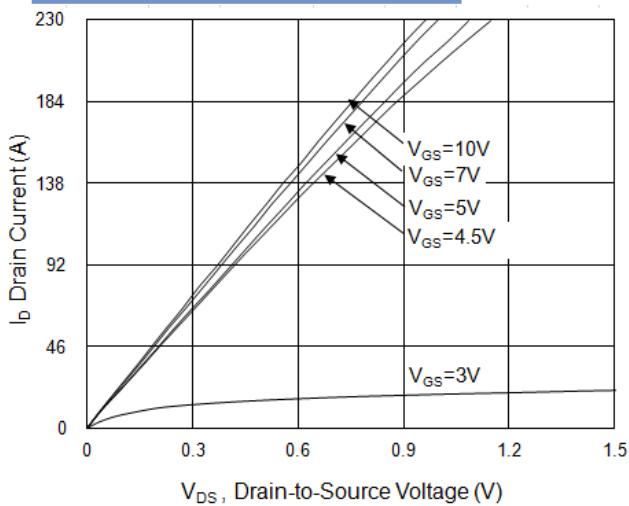
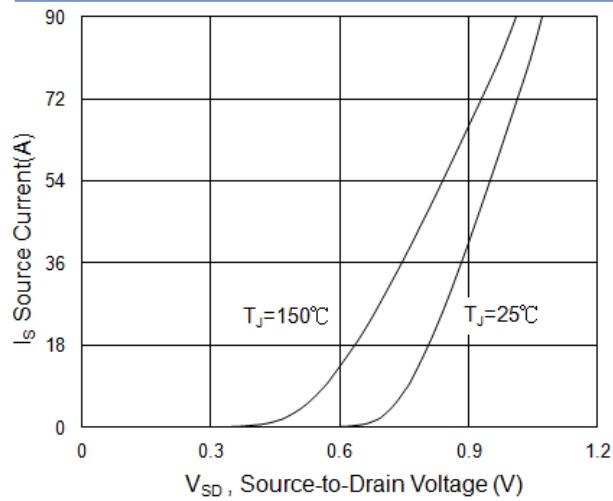
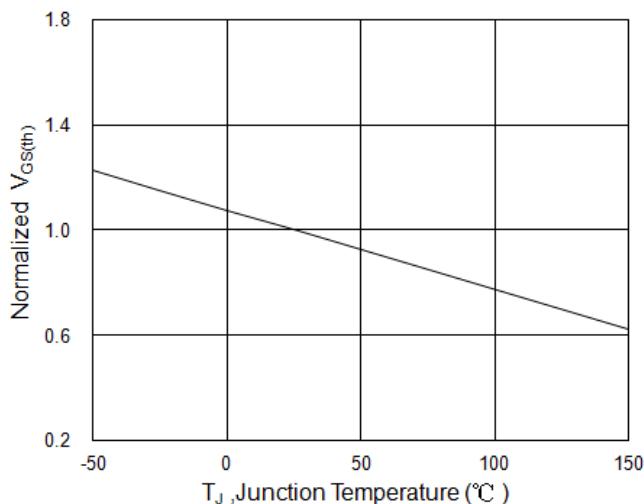
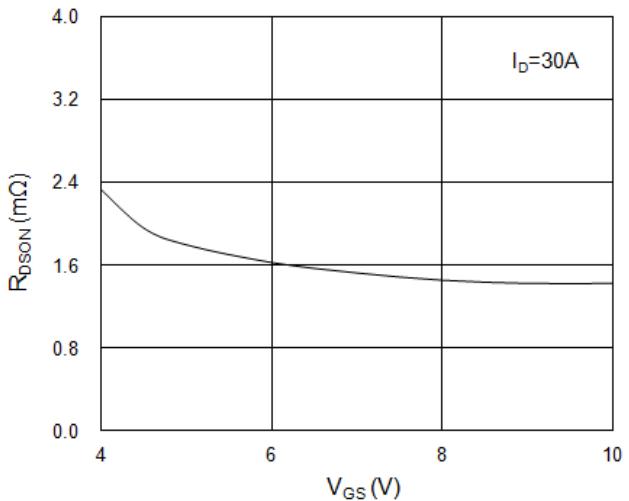
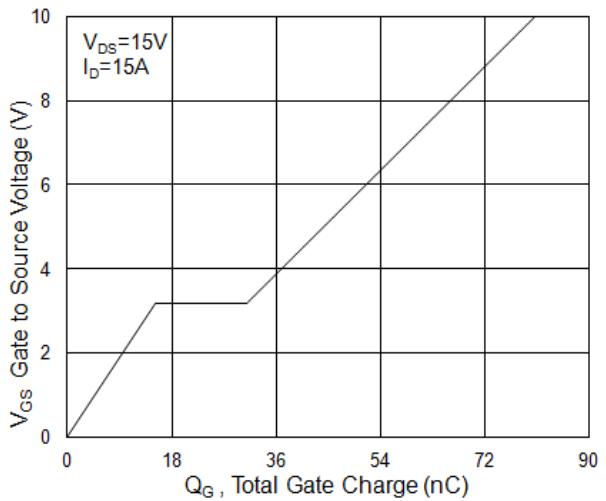
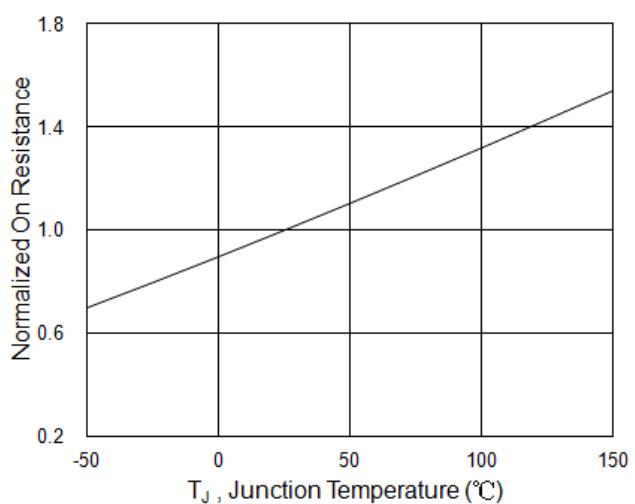
Symbol	Parameter	Conditions	Min.	Typ.	Max.	Unit
I_s	Continuous Source Current ^{1,6}	$V_G=V_D=0\text{V}$, Force Current	---	---	117	A
I_{SM}	Pulsed Source Current ^{2,6}		---	---	234	A
V_{SD}	Diode Forward Voltage ²	$V_{GS}=0\text{V}$, $I_s=1\text{A}$	---	---	1.2	V

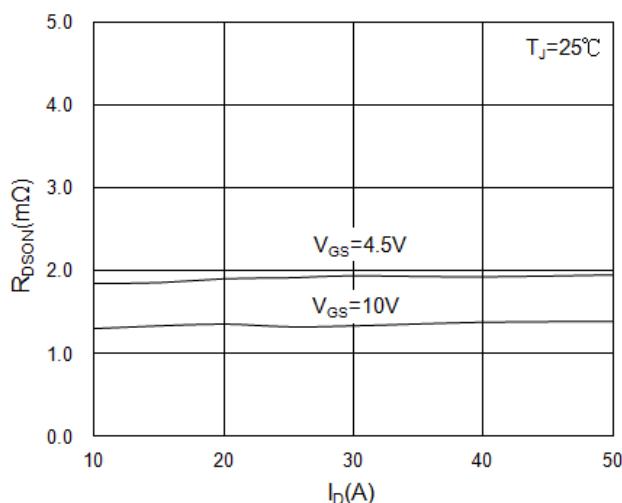
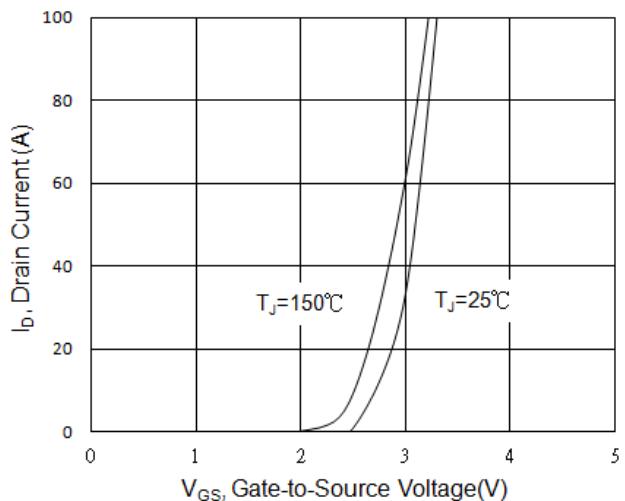
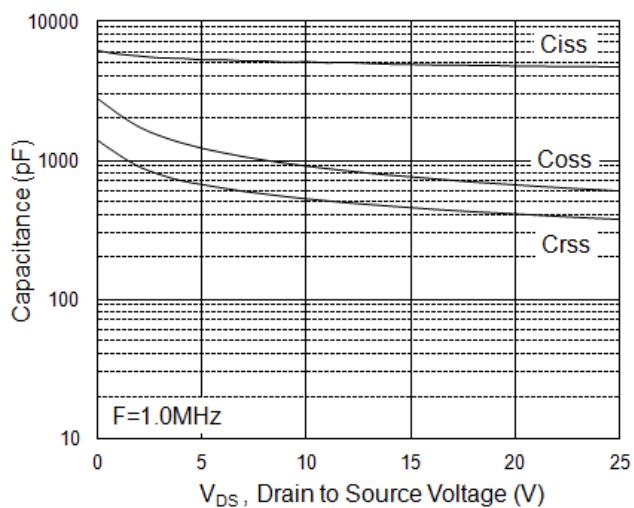
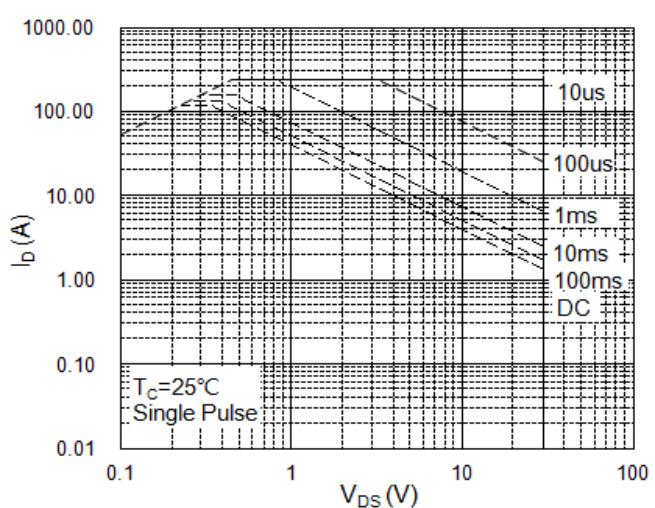
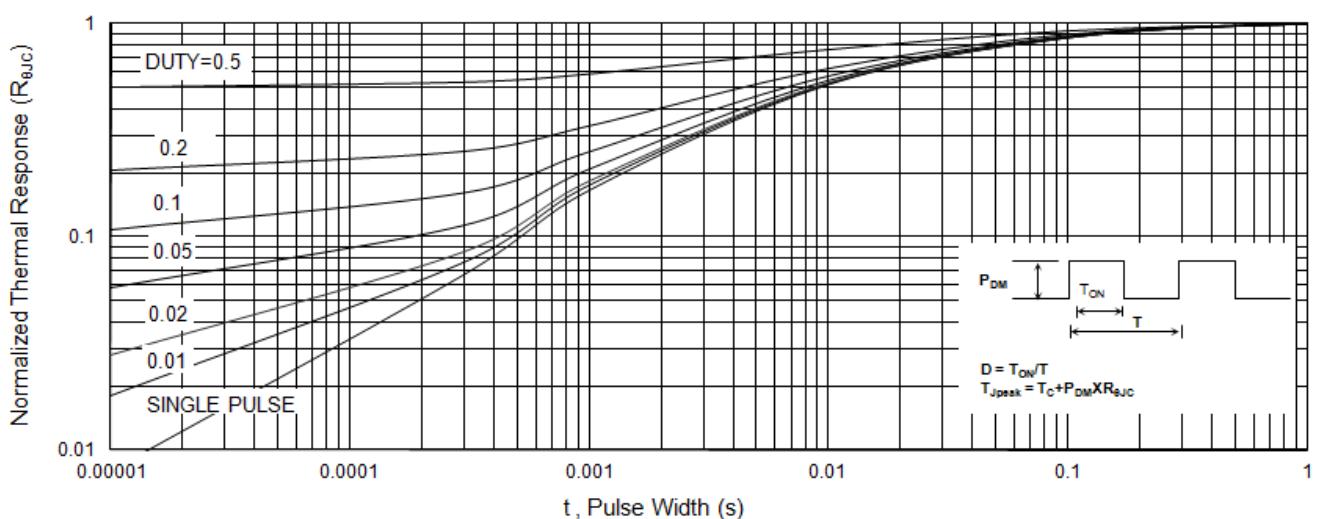
Note :

- 1.The data tested by surface mounted on a 1 inch² FR-4 board with 2OZ copper.
- 2.The data tested by pulsed , pulse width $\leq 300\mu\text{s}$, duty cycle $\leq 2\%$
- 3.The EAS data shows Max. rating . The test condition is $V_{DD}=50\text{V}$, $V_{GS}=10\text{V}$, $L=0.1\text{mH}$.
- 4.The power dissipation is limited by 150°C junction temperature
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- 6.The data is theoretically the same as I_D and I_{DM} , in real applications , should be limited by total power dissipation.

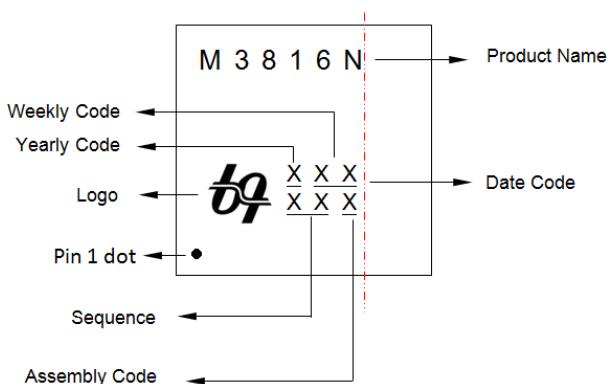
Die 1 Typical Characteristics

Fig.1 Typical Output Characteristics

Fig.2 On-Resistance vs. Gate-Source

Fig.3 Forward Characteristics of Reverse

Fig.4 Gate-Charge Characteristics

Fig.5 Normalized $V_{GS(th)}$ vs. T_J

Fig.6 Normalized $R_{DS(on)}$ vs. T_J

Dual N-Channel Fast Switching MOSFET

Fig.7 Drain-Source On-State Resistance

Fig.8 Transfer Characteristics

Fig.9 Capacitance

Fig.10 Safe Operating Area

Fig.11 Normalized Maximum Transient Thermal Impedance

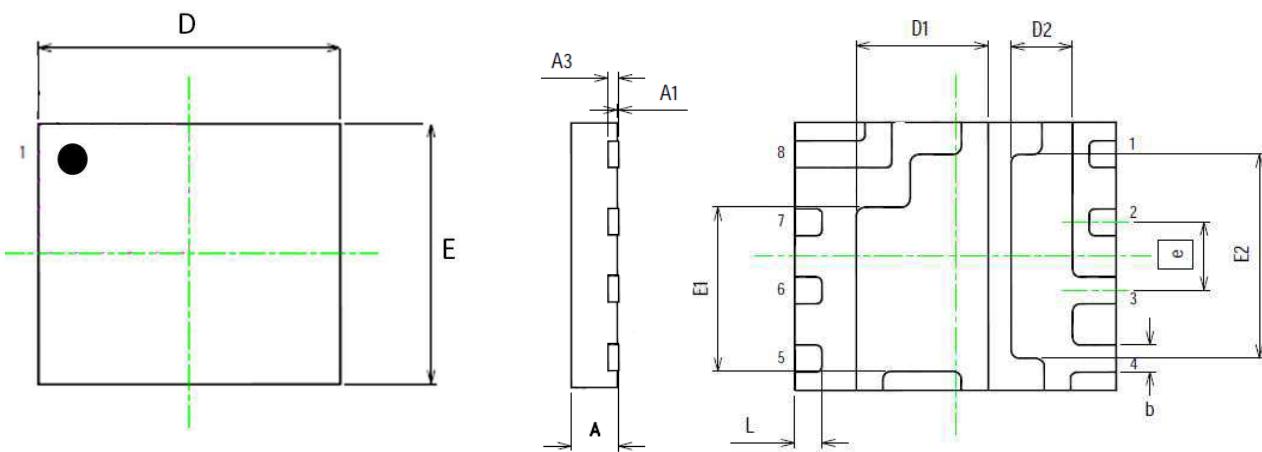
Die 2 Typical Characteristics

Fig.1 Typical Output Characteristics

Fig.3 Forward Characteristics of Reverse

Fig.5 Normalized $V_{GS(th)}$ vs. T_J

Fig.2 On-Resistance vs. Gate-Source

Fig.4 Gate-Charge Characteristics

Fig.6 Normalized $R_{DS(on)}$ vs. T_J

Dual N-Channel Fast Switching MOSFET

Fig.7 Drain-Source On-State Resistance

Fig.8 Transfer Characteristics

Fig.9 Capacitance

Fig.10 Safe Operating Area

Fig.11 Normalized Maximum Transient Thermal Impedance

Top Marking



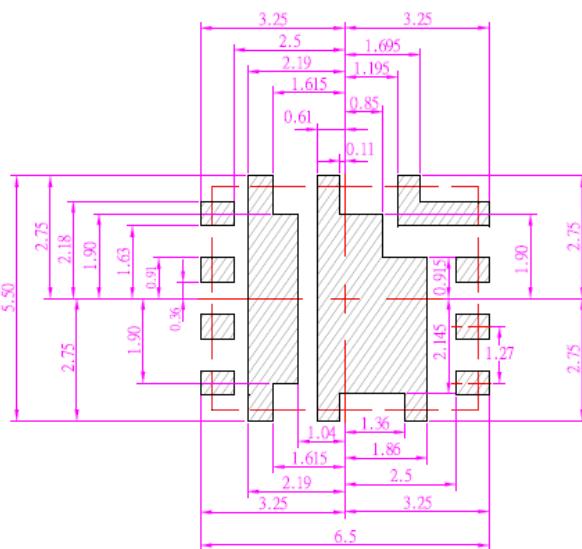
DFN 5X6 Package Outline Drawing



SYMBOLS	Millimeters		
	MIN	NOM	MAX
A	0.80	0.90	1.00
A1	0.00	0.02	0.05
A3	—	0.203	—
b	0.40	0.50	0.60
D	—	6.00	—
E	—	5.00	—
e	—	1.27	—
D1	2.37	2.47	2.57
E1	2.96	3.06	3.16
D2	1.05	1.15	1.25
E2	3.70	3.80	3.90
L	0.40	0.50	0.60

Note:

1. PACKAGE BODY SIZES EXCLUDE MOLD FLASH AND GATE BURRS.



LAND PATTERN RECOMMENDATION (Unit :mm)